


<b>Search Notes</b>  	<b>Application/Control No.</b>  10750028	<b>Applicant(s)/Patent Under Reexamination</b>  MEYERS ET AL.
	<b>Examiner</b>  Shin, Kyung H	<b>Art Unit</b>  2143

SEARCHED			
Class	Subclass	Date	Examiner
709	203, 230, 238	1/31/08	KHS
715	733	1/31/08	KHS

SEARCH NOTES			
Search Notes		Date	Examiner
101, Double Ptn checked		1/31/08	KHS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner